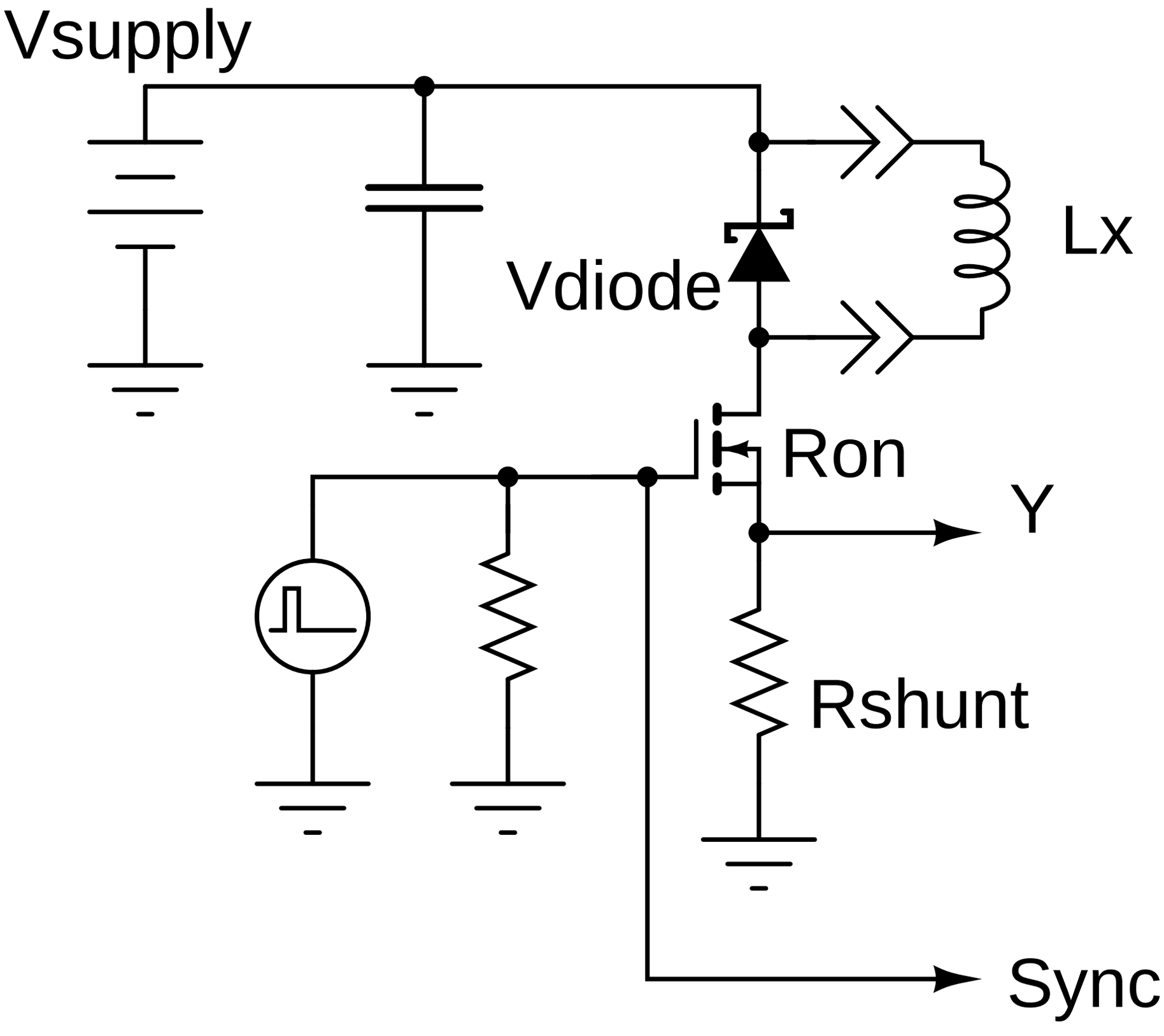Inductor Saturation Testing Scheme